FORM PTO-1449

APPLICANT'S INFORMATION DISCLOSURE **STATEMENT**

(use several sheets if necessary)

SERIAL NO. CASE NO. 08/853,323 7103/30 FILING DATE **GROUP ART UNIT** 3203

May 8, 1997

APPLICANT(S): Homayoun Talieh et al.

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER DOCUMENT		U.S. PATEN	T DOCUMENTS	CLASS/	FILING	
INITIAL		NUMBER	DATE	NAME	SUBCLASS	DATE
(9N)	A1	619,399	02/1899	Fischer		
•	A2	3,447,306	06/1969	Jakimcius		
	A3	3,654,739	04/1972	Stoy et al.	,	
	A4	3,753,269	08/1973	Budman		
	A5	3,906,678	09/1975	Roth		
	A6	4,016,857	04/1977	Hall .	«	
	A7	4,347,689	09/1982	Hammond		
	A8	4,416,090	11/1983	Jonasson	-	
	A9	4,593,495	06/1986	Kawakami et al.	•	
	A10	4,628,640	12/1986	Johannsen	-	
	A11	4,642,943	02/1987	Taylor, Jr.		
	A12	4,704,823	11/1987	Steinback	*	
	A13	4,811,522	03/1989	Gill, Jr.		
	A14	4,934,102	06/1990	Leach et al.		
	A15	4,941,293	07/1990	Ekhoff	-	
	A16	5,081,795	01/1992	Tanaka et al.		
	A17	5,205,082	04/1993	Shendon et al.		
	A18	5,212,910	05/1993	Breivogel		
	A19	5,230,184	07/1993	Bukhman		
	A20	5,232,875	08/1993	Tuttle et al.	-	
	A21	5,246,525	09/1993	Sato	•	
	A22	5,274,964	01/1994	Simpson et al.		
	A23	5,276,999	01/1994	Bando-		
	A24	5,287,663	02/1994	Pierce et al.	-	
	A25	5,297,361	03/1994	Baldy et al.		
	A26	5,329,732	07/1994	Karlsrud et al.		
	A27	5,329,734	07/1994	Yu		
	A28	5,335,453	08/1994	Baldy et al.		
W	A29	5,399,125	03/1995	Dozier		
V	A30	5,456,627	10/1995	Jackson et al.		

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PATE	COUNTRY	CLASS/ SUBCLASS	TRANSI YES	LATION NO
GN	A31	EP 517 594	12192	EPO	•		
611	A32	EP 517 595	12/92	EPO			
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FORM PTO-1449	1018	SERIAL NO.		CASE NO.
•	<i></i>	A A	08/853,323	7103/30
LIST OF PATENTS AND PUBLIC	ATIONS FOR	FILING DATE		GROUP ART UNIT
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FOREIGN PATENT DOCUMENTS

	EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSL YES	ATION NO
C	(ON	A33	2269552	11 1990	Japan			
	<u> </u>	A34	2269553	11/19/90	Japan			
•	W	A35	62162466	17/8/	Japan.			
	Λ,	A36	63267155	11/8/8	Japan			
١	21/20	A37	7111256	1 64 (1975	Japan			
λ	DIN	A38	JP 59-232768	12/1984	Japan			
		A39	JP 63200965	08/1988	Japan			
		A40	JP 63251166	10/1988	Japan			
	Γ .	A41	JP 4-250967	09/1992	Japan			
	1012	A42	DE 3411 120 A1	03/1983	Germany			
	V JOS	A43	PCT WO 94/17957	08/1994	PCT			
	1 ON	A44	2007784	62/1994	Russia	<u> </u>		

EXAMINER INITIAL		OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)
6N	A45	"A New Pad and Equipment Development for ILD Planarization" by Toshiyasu Beppu, Motoyuki Obara and Yausuo Minamikawa, Semiconductor World, January, 1994, MY 3/17/94
GN	A46	"Application of Chemical Mechanical Polishing to the Fabrication of VLSI Circuit Interconnections", William J. Patrick, William L. Guthrie, Charles L. Stadley and Paul M. Schiable, J. Electrochem. Soc., Vol. 138, No. 6, June 1991,pp. 1778-1784
GN	A47	"Theory & Practice of Lubrication for Engineers", Dudley Fuller, Wiley-Interscience, 1st ed., pp. 22-25 and 86
CON	A48	Practical Ideas, June 1994, page 67

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FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

(use several sheets if necessary)

RIAL NO. 08/853,323

CASE NO.

ASE NO. 7102*1*

FILING DATE

GROUP ART UNIT

May 8, 1997 3203

APPLICANT(S): Homayoun Talieh et al.

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

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6N	A1	619,399	02/1899	Fischer	-	·····
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(S1V	A31	EP 517 594		EPO	-		
AN	A32	EP 517 595		EPO			
EXAMINER	6.1	16UTEN	DATE	CONSIDERED 2/	9/98		

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FORM PTO-1449	SERIAL NO. 08/853,323	CASE NO. 7103/30	port
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(use several sheets if necessary)	APPLICANT(S): Homayoun Tali	ieh et al.	ı

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1	GN	A48	Practical Ideas, June 1994, page 67					

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